



# 16-BIT, 1.25 MSPS, PSEUDO-BIPOLAR, FULLY DIFFERENTIAL INPUT, MICRO POWER SAMPLING ANALOG-TO-DIGITAL CONVERTER WITH PARALLEL INTERFACE

### **FEATURES**

- Pseudo-Bipolar, Fully Differential Input, -V<sub>REF</sub> to V<sub>REF</sub>
- 16-Bit NMC at 1.25 MSPS
- ±2 LSB INL Max, -1/+1.25 LSB DNL
- 90 dB SNR, -95 dB THD at 100 kHz Input
- Zero Latency
- Internal 4.096 V Reference
- High-Speed Parallel Interface
- Single 5 V Analog Supply
- Wide I/O Supply: 2.7 V to 5.25 V
- Low Power: 155 mW at 1.25 MHz Typ
- Pin Compatible With ADS8412/8402
- 48-Pin TQFP Package

## **APPLICATIONS**

- DWDM
- Instrumentation
- High-Speed, High-Resolution, Zero Latency Data Acquisition Systems
- Transducer Interface
- Medical Instruments
- Communications

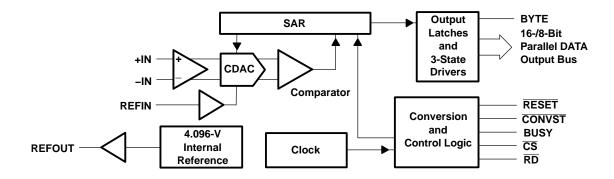
## **DESCRIPTION**

The ADS8406 is a 16-bit, 1.25 MHz A/D converter with an internal 4.096-V reference. The device includes a 16-bit capacitor-based SAR A/D converter with inherent sample and hold. The ADS8406 offers a full 16-bit interface and an 8-bit option where data is read using two 8-bit read cycles.

The ADS8406 has a pseudo-bipolar, fully differential input. It is available in a 48-lead TQFP package and is characterized over the industrial -40°C to 85°C temperature range.

#### **High Speed SAR Converter Family**

Type/Speed	500 kHz	580 kHz	750 MHZ	1.25 MHz	2 MHz	3 MHz	4 MHz
18 Bit Pseudo-Diff	ADS8383	ADS8381					
40 0'' 0 1 0'''			ADS8371	ADS8401	ADS8411		
16 Bit Pseudo-Diff				ADS8405			
16 Bit Pseudo Bipolar,				ADS8402	ADS8412		
Fully Differential				ADS8406			
14 Bit Pseudo-Diff				ADS7890 (S)		ADS7891	
12 Bit Pseudo-Diff							ADS7881





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



## ORDERING INFORMATION(1)

MODEL	MAXIMUM INTEGRAL LINEARITY (LSB)	MAXIMUM DIFFERENTIAL LINEARITY (LSB)	NO MISSING CODES RESOLUTION (BIT)	PACKAGE TYPE	PACKAGE DESIG- NATOR	TEMPERA- TURE RANGE	ORDERING INFORMATION	TRANSPORT MEDIA QUANTITY			
ADS8406I	-4 to +4	-2 to +2	15	48 Pin TQFP	48 Pin	555	PFB	4000 / 0500	-40°C to 85°C	ADS8406IPFBT	Tape and reel 250
AD364001	-4 to +4	-2 10 +2	13		FFB	-40 C to 65 C	ADS8406IPFBR	Tape and reel 1000			
ADS8406IB	-2 to +2	-1 to +1.25	16	48 Pin	48 Pin	48 Pin PFB	-40°C to 85°C	ADS8406IBPFBT	Tape and reel 250		
AD30400IB	-2 to +2	-2 to +2 -1 to +1.25	16	TQFP	FFB	-40 C to 85 C	ADS8406IBPFBR	Tape and reel 1000			

<sup>(1)</sup> For the most current specifications and package information, refer to our website at www.ti.com.

## **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range unless otherwise noted(1)

				UNIT		
	Valtana	+IN to AGND		-0.4 V to +VA + 0.1 V		
	Voltage	-IN to AGND		-0.4 V to +VA + 0.1 V		
		+VA to AGNI	)	−0.3 V to 7 V		
	Voltage range	+VBD to BD0	GND	−0.3 V to 7 V		
		+VA to +VBD		–0.3 V to 2.55 V		
	Digital input volta	ge to BDGND		-0.3 V to +VBD + 0.3 V		
	Digital output volt	tage to BDGNI	)	-0.3 V to +VBD + 0.3 V		
T <sub>A</sub>	Operating free-ai	r temperature	range	-40°C to 85°C		
T <sub>stg</sub>	Storage tempera	ture range		−65°C to 150°C		
	Junction tempera	ture (T <sub>J</sub> max)		150°C		
	TOED poolsogo	Power dissipa	ation	$(T_J Max - T_A)/\theta_{JA}$		
	TQFP package	$\theta_{JA}$ thermal in	mpedance	86°C/W		
	Load tomporative		Vapor phase (60 sec)	215°C		
	Lead temperature	e, solueling	Infrared (15 sec)	220°C		

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



## **SPECIFICATIONS**

 $T_{A} = -40^{\circ}\text{C to } 85^{\circ}\text{C}, \text{ +VA} = 5 \text{ V}, \text{ +VBD} = 3 \text{ V or 5 V}, V_{ref} = 4.096 \text{ V}, f_{SAMPLE} = 1.25 \text{ MHz (unless otherwise noted)}$ 

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT		
ANALO	G INPUT					<u> </u>			
	Full-scale input voltage (1)		+IN - (-IN)	-V <sub>ref</sub>		$V_{ref}$	V		
	Ab a data famata adta na		+IN	-0.2		V <sub>ref</sub> + 0.2			
	Absolute input voltage		-IN	-0.2		$V_{ref} + 0.2$	V		
	Input capacitance				25		pF		
	Input leakage current				0.5		nA		
SYSTEM	M PERFORMANCE					<u> </u>			
	Resolution				16		Bits		
	No missing codes	ADS8406I		15			Bits		
	No missing codes	ADS8406IB		16			DIIS		
INII	Integral linearity (2)(3)	ADS8406I		-4	±2	4	LCD		
INL	NL Integral linearity (2)(3)	ADS8406IB		-2	±1	2	LSB		
DNL	Differential linearity	ADS8406I		-2	±1	2	LSB		
DINL	Differential linearity	ADS8406IB		-1	±0.5	1.25	LOD		
_	Offset error <sup>(4)</sup>	ADS8406I		-2.5	±1	2.5	mV		
E <sub>O</sub>	Oliset ellor	ADS8406IB		-1.5	±0.5	1.5	mV		
_	Gain error <sup>(4)(5)</sup>	Cain arrar(4)(5)	Onin amar(4)(5)	ADS8406I		-0.12		0.12	0/ EC
E <sub>G</sub>	Gain end (**/(**)	ADS8406IB		-0.098		0.098	%FS		
CMRR	Common mode rejection	ratio	At dc (0.2 V around V <sub>ref</sub> /2)		80		dB		
CIVIKK	Common mode rejection i	allo	$+IN - (-IN) = 1 V_{pp} \text{ at } 1 \text{ MHz}$		80		иБ		
PSRR	DC Power supply rejection	n ratio	At 7FFFh output code, +VA = 4.75 V to 5.25 V, V <sub>ref</sub> = 4.096 V <sup>(4)</sup>		2		LSB		
SAMPLI	ING DYNAMICS					<u> </u>			
	Conversion time			500		650	ns		
	Acquisition time			150			ns		
	Throughput rate					1.25	MHz		
	Aperture delay				2		ns		
	Aperture jitter				25		ps		
	Step response				100		ns		
	Overvoltage recovery				100		ns		
DYNAM	IC CHARACTERISTICS								
THD	Total harmonic distortion	(6)	$V_{IN} = 8 V_{pp}$ at 100 kHz		-95		dB		
11110	Total Harmonic distortion		$V_{IN} = 8 V_{pp}$ at 500 kHz		-90		ub_		
SNR	Signal-to-noise ratio		$V_{IN} = 8 V_{pp}$ at 100 kHz		90		dB		
SINAD	Signal-to-noise + distortio	n	$V_{IN} = 8 V_{pp}$ at 100 kHz		88		dB		
SFDR	Spurious free dynamic range		$V_{IN} = 8 V_{pp}$ at 100 kHz		95		dB		
J. D.	Spanoao noo aynamo tai	·9~	$V_{IN} = 8 V_{pp}$ at 500 kHz	93			4D		
	-3dB Small signal bandwi				5		MHz		
EXTERN	NAL VOLTAGE REFEREN	CE INPUT							
	Reference voltage at REF	IN, V <sub>ref</sub>		2.5	4.096	4.2	V		
	Reference resistance (7)				500		$k\Omega$		

- (1) Ideal input span, does not include gain or offset error.
- LSB means least significant bit
- This is endpoint INL, not best fit.
- Measured relative to an ideal full-scale input [+IN (-IN)] of 8.192 V
  This specification does not include the internal reference voltage error and drift.
- Calculated on the first nine harmonics of the input frequency
- (6) (7) Can vary ±20%



# **SPECIFICATIONS** (continued)

 $T_A = -40$ °C to 85°C, +VA = 5 V, +VBD = 3 V or 5 V,  $V_{ref} = 4.096$  V,  $f_{SAMPLE} = 1.25$  MHz (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
INTER	NAL REFERENCE OUTPUT		·				
	Internal reference start-up	time	From 95% (+VA) with 1-μF storage capacitor			120	ms
V <sub>ref</sub>	Reference voltage		IOUT = 0	4.065	4.096	4.13	V
	Source current		Static load			10	μA
	Line regulation		+VA = 4.75 to 5.25 V		0.6		mV
	Drift		IOUT = 0		36		PPM/°C
DIGITA	AL INPUT/OUTPUT						
	Logic family — CMOS						
$V_{IH}$	High level input voltage	High level input voltage		+VBD - 1	+VBD + 0.3		
$V_{IL}$	Low level input voltage		I <sub>IL</sub> = 5 μA	-0.3	0.8		V
$V_{OH}$	High level output voltage		I <sub>OH</sub> = 2 TTL loads	+VBD - 0.6	+VBD		
$V_{OL}$	Low level output voltage		I <sub>OL</sub> = 2 TTL loads	0		0.4	
	Data format — 2's comple	ment					
POWE	R SUPPLY REQUIREMENTS	S					
	Dower aupply voltage	+VBD		2.7	3	5.25	V
	Power supply voltage	+VA		4.75	5	5.25	V
	Supply current, +VA <sup>(8)</sup>		f <sub>s</sub> = 1.25 MHz		31	34	mA
$P_D$	Power dissipation <sup>(8)</sup>		f <sub>s</sub> = 1.25 MHz		155	170	mW
TEMP	ERATURE RANGE						
T <sub>A</sub>	Operating free-air tempera	ature		-40		85	°C

<sup>(8)</sup> This includes only +VA current. +VBD current is typically 1 mA with 5-pF load capacitance on output pins.



## TIMING CHARACTERISTICS

All specifications typical at  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = +VBD = 5 V (1)(2)(3)

	PARAMETER	MIN	TYP	MAX	UNIT
CONV	Conversion time	500		650	ns
ACQ	Acquisition time	150			ns
pd1	CONVST low to BUSY high		40		ns
pd2	Propagation delay time, end of conversion to BUSY low		5		ns
t <sub>w1</sub>	Pulse duration, CONVST low	20			ns
t <sub>su1</sub>	Setup time, CS low to CONVST low	0			ns
w2	Pulse duration, CONVST high	20			ns
	CONVST falling edge jitter			10	ps
t <sub>w3</sub>	Pulse duration, BUSY signal low	Min(t <sub>ACQ</sub> )			ns
w4	Pulse duration, BUSY signal high		610		ns
t <sub>h1</sub>	Hold time, First data bus data transition (RD low, or CS low for read cycle, or BYTE input changes) after CONVST low	40			ns
t <sub>d1</sub>	Delay time, $\overline{CS}$ low to $\overline{RD}$ low (or BUSY low to $\overline{RD}$ low when $\overline{CS}$ = 0)	0			ns
su2	Setup time, RD high to CS high	0			ns
t <sub>w5</sub>	Pulse duration, RD low time	50			ns
en	Enable time, RD low (or CS low for read cycle) to data valid			20	ns
d2	Delay time, data hold from RD high	0			ns
d3	Delay time, BYTE rising edge or falling edge to data valid	2		20	ns
w <sub>6</sub>	Pulse duration, RD high	20			ns
w <sub>7</sub>	Pulse duration, CS high time	20			ns
h2	Hold time, last $\overline{RD}$ (or $\overline{CS}$ for read cycle ) rising edge to $\overline{CONVST}$ falling edge	50			ns
su3	Setup time, BYTE transition to RD falling edge	0			ns
h3	Hold time, BYTE transition to RD falling edge	0			ns
t <sub>dis</sub>	Disable time, $\overline{\text{RD}}$ high ( $\overline{\text{CS}}$ high for read cycle) to 3-stated data bus			20	ns
d5	Delay time, end of conversion to MSB data valid			10	ns
su4	Byte transition setup time, from BYTE transition to next BYTE transition	50			ns
d6	Delay time, CS rising edge to BUSY falling edge	50			ns
t <sub>d7</sub>	Delay time, BUSY falling edge to CS rising edge	50			ns
su(AB)	Setup time, from the falling edge of $\overline{\text{CONVST}}$ (used to start the valid conversion) to the next falling edge of $\overline{\text{CONVST}}$ (when $\overline{\text{CS}}$ = 0 and $\overline{\text{CONVST}}$ used to abort) or to the next falling edge of $\overline{\text{CS}}$ (when $\overline{\text{CS}}$ is used to abort)	60		500	ns
su5	Setup time, falling edge of $\overline{\text{CONVST}}$ to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$			ns
h4	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIM	V(t <sub>CONV</sub> )	ns

All input signals are specified with  $t_r$  =  $t_f$  = 5 ns (10% to 90% of +VBD) and timed from a voltage level of  $(V_{IL} + V_{IH})/2$ . See timing diagrams.

<sup>(2)</sup> (3) All timings are measured with 20-pF equivalent loads on all data bits and BUSY pins.



## TIMING CHARACTERISTICS

All specifications typical at  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = 5 V, +VBD = 3 V<sup>(1)(2)(3)</sup>

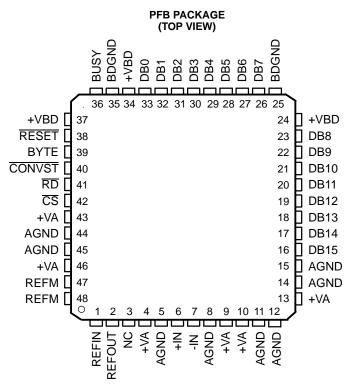
	PARAMETER	MIN	TYP MAX	UNIT
t <sub>CONV</sub>	Conversion time	500	650	ns
t <sub>ACQ</sub>	Acquisition time	150		ns
t <sub>pd1</sub>	CONVST low to BUSY high		50	ns
t <sub>pd2</sub>	Propagation delay time, end of conversion to BUSY low		10	ns
t <sub>w1</sub>	Pulse duration, CONVST low	20		ns
t <sub>su1</sub>	Setup time, CS low to CONVST low	0		ns
t <sub>w2</sub>	Pulse duration, CONVST high	20		ns
	CONVST falling edge jitter		10	ps
t <sub>w3</sub>	Pulse duration, BUSY signal low	Min(t <sub>ACQ</sub> )		ns
t <sub>w4</sub>	Pulse duration, BUSY signal high		610	ns
t <sub>h1</sub>	Hold time, first data bus transition (RD low, or CS low for read cycle, or BYTE or BUS 16/16 input changes) after CONVST low	40		ns
t <sub>d1</sub>	Delay time, $\overline{CS}$ low to $\overline{RD}$ low (or BUSY low to $\overline{RD}$ low when $\overline{CS}$ = 0)	0		ns
$t_{su2}$	Setup time, RD high to CS high	0		ns
$t_{w5}$	Pulse duration, RD low	50		ns
t <sub>en</sub>	Enable time, $\overline{\text{RD}}$ low (or $\overline{\text{CS}}$ low for read cycle) to data valid		30	ns
$t_{d2}$	Delay time, data hold from RD high	0		ns
t <sub>d3</sub>	Delay time, BYTE rising edge or falling edge to data valid	2	30	ns
t <sub>w6</sub>	Pulse duration, RD high time	20		ns
t <sub>w7</sub>	Pulse duration, CS high time	20		ns
t <sub>h2</sub>	Hold time, last $\overline{RD}$ (or $\overline{CS}$ for read cycle ) rising edge to $\overline{CONVST}$ falling edge	50		ns
$t_{su3}$	Setup time, BYTE transition to RD falling edge	0		ns
t <sub>h3</sub>	Hold time, BYTE transition to RD falling edge	0		ns
$t_{dis}$	Disable time, $\overline{\text{RD}}$ high ( $\overline{\text{CS}}$ high for read cycle) to 3-stated data bus		30	ns
$t_{d5}$	Delay time, end of conversion to MSB data valid		20	ns
t <sub>su4</sub>	Byte transition setup time, from BYTE transition to next BYTE transition	50		ns
t <sub>d6</sub>	Delay time, CS rising edge to BUSY falling edge	50		ns
t <sub>d7</sub>	Delay time, BUSY falling edge to CS rising edge	50		ns
t <sub>su(AB)</sub>	Setup time, from the falling edge of CONVST (used to start the valid conversion) to the next falling edge of CONVST (when CS = 0 and CONVST used to abort) or to the next falling edge of CS (when CS is used to abort)	70	500	ns
t <sub>su5</sub>	Setup time, falling edge of $\overline{\text{CONVST}}$ to read valid data (MSB) from current conversion	$MAX(t_{CONV}) + MAX(t_{d5})$		ns
t <sub>h4</sub>	Hold time, data (MSB) from previous conversion hold valid from falling edge of CONVST		MIN(t <sub>CONV</sub> )	ns

<sup>(1)</sup> All input signals are specified with  $t_r = t_f = 5$  ns (10% to 90% of +VBD) and timed from a voltage level of  $(V_{IL} + V_{IH})/2$ . (2) See timing diagrams.

All timings are measured with 20-pF equivalent loads on all data bits and BUSY pins.



## **PIN ASSIGNMENTS**



NC - No connection

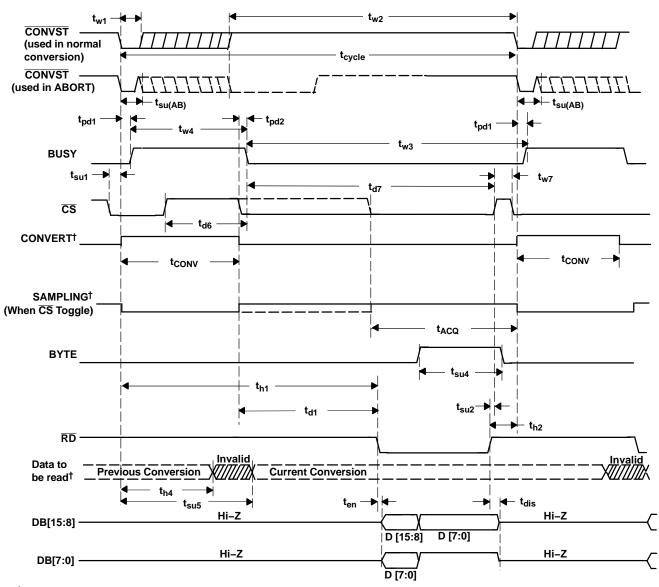


## **Terminal Functions**

NAME	NO.	I/O	DESCRIPTION				
AGND	5, 8, 11, 12, 14, 15, 44, 45	_	Analog ground				
BDGND	25, 35	-	Digital ground for bus interface	digital supply			
BUSY	36	0	Status output. High when a co	nversion is in progress.			
BYTE	39	I	Byte select input. Used for 8-b significant bits is folded back to		ck 1: Low byte D[7:0] of the 16 most gnificant pins DB[15:8].		
CONVST	40	I	Convert start. The falling edge period.	of this input ends the acquis	sition period and starts the hold		
CS	42	I	Chip select. The falling edge o	f this input starts the acquisi	tion period.		
Data Dua			8-Bit B	us	16-Bit Bus		
Data Bus			BYTE = 0	BYTE = 1	BYTE = 0		
DB15	16	0	D15 (MSB)	D7	D15 (MSB)		
DB14	17	0	D14	D6	D14		
DB13	18	0	D13	D5	D13		
DB12	19	0	D12	D4	D12		
DB11	20	0	D11	D3	D11		
DB10	21	0	D10	D2	D10		
DB9	22	0	D9	D1	D9		
DB8	23	0	D8	D0 (LSB)	D8		
DB7	26	0	D7	All ones	D7		
DB6	27	0	D6	All ones	D6		
DB5	28	0	D5	All ones	D5		
DB4	29	0	D4	All ones	D4		
DB3	30	0	D3	All ones	D3		
DB2	31	0	D2	All ones	D2		
DB1	32	0	D1	All ones	D1		
DB0	33	0	D0 (LSB)	All ones	D0 (LSB)		
-IN	7	I	Inverting input channel	<u> </u>			
+IN	6	I	Non inverting input channel				
NC	3	-	No connection				
REFIN	1	I	Reference input				
REFM	47, 48	I	Reference ground				
REFOUT	2	0	Reference output. Add 1-µF careference is used.	pacitor between the REFOL	JT pin and REFM pin when internal		
RESET	38	I	Current conversion is aborted and output latches are cleared (set to zeros) when this pin is asserted low. RESET works independently of CS.				
RD	41	I	Synchronization pulse for the parallel output. When $\overline{\text{CS}}$ is low, this serves as the output enable and puts the previous conversion result on the bus.				
+VA	4, 9, 10, 13, 43, 46	_	Analog power supplies, 5-V do				
+VBD	24, 34, 37	-	Digital power supply for bus				



## **TIMING DIAGRAMS**



<sup>†</sup>Signal internal to device

Figure 1. Timing for Conversion and Acquisition Cycles With CS and RD Toggling



## **TIMING DIAGRAMS (continued)**

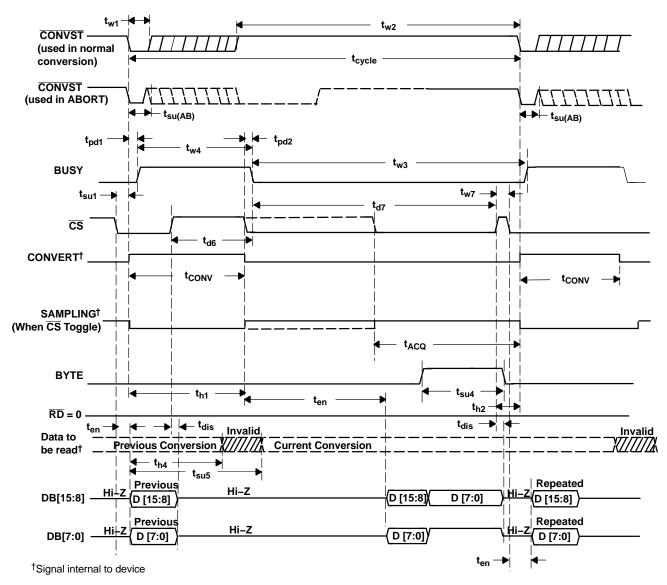


Figure 2. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  Toggling,  $\overline{\text{RD}}$  Tied to BDGND



## **TIMING DIAGRAMS (continued)**

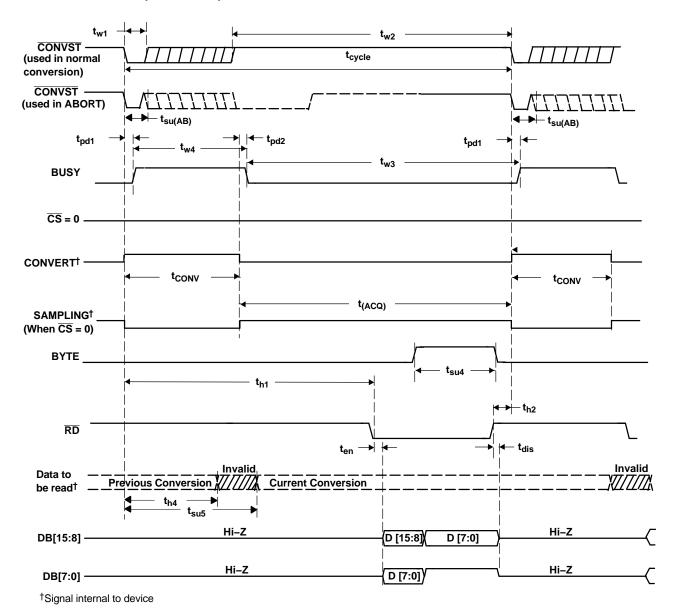
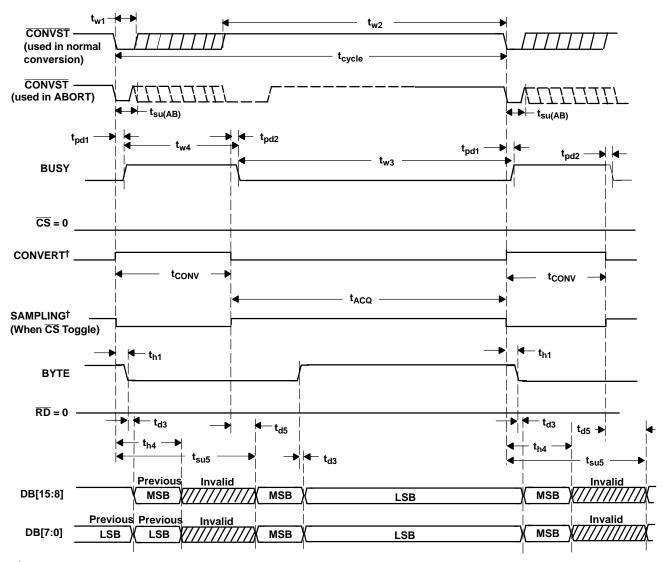


Figure 3. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  Tied to BDGND,  $\overline{\text{RD}}$  Toggling



## **TIMING DIAGRAMS (continued)**



<sup>†</sup>Signal internal to device

Figure 4. Timing for Conversion and Acquisition Cycles With  $\overline{\text{CS}}$  and  $\overline{\text{RD}}$  Tied to BDGND—Auto Read

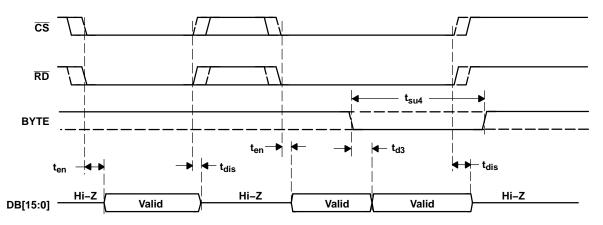


Figure 5. Detailed Timing for Read Cycles



### TYPICAL CHARACTERISTICS

At  $-40^{\circ}$ C to  $85^{\circ}$ C, +VA = 5 V, +VBD = 5 V, REFIN = 4.096 V (internal reference used) and  $f_{sample}$  = 1.25 MHz (unless otherwise noted)

# HISTOGRAM (DC Code Spread) HALF SCALE 131071 CONVERSIONS

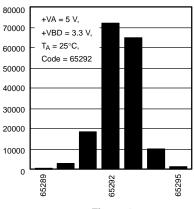


Figure 6.

# SIGNAL-TO-NOISE AND DISTORTION vs FREE-AIR TEMPERATURE

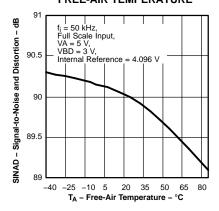


Figure 8.

#### SIGNAL-TO-NOISE RATIO vs FREE-AIR TEMPERATURE

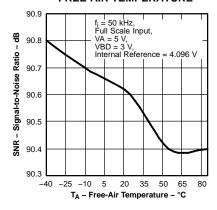


Figure 7.

# EFFECTIVE NUMBER OF BITS vs FREE-AIR TEMPERATURE

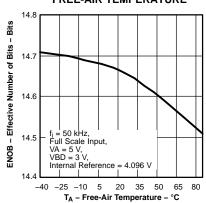


Figure 9.



# SPURIOUS FREE DYNAMIC RANGE vs FREE-AIR TEMPERATURE

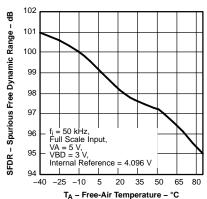


Figure 10.

#### SIGNAL-TO-NOISE RATIO vs INPUT FREQUENCY

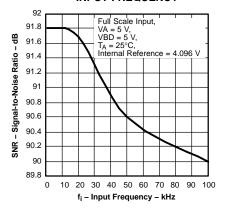


Figure 12.

# SIGNAL-TO-NOISE AND DISTORTION VS INPUT FREQUENCY

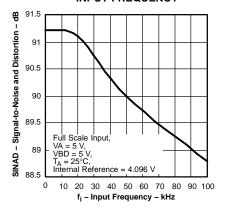


Figure 14.

# TOTAL HARMONIC DISTORTION vs FREE-AIR TEMPERATURE

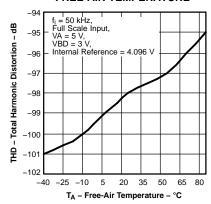


Figure 11.

# EFFECTIVE NUMBER OF BITS VS INPUT FREQUENCY

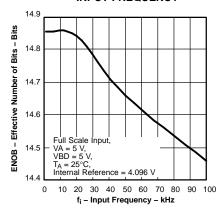


Figure 13.

# SPURIOUS FREE DYNAMIC RANGE vs INPUT FREQUENCY

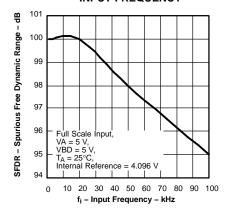


Figure 15.



# TOTAL HARMONIC DISTORTION VS INPUT FREQUENCY

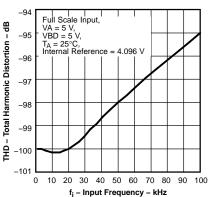


Figure 16.

#### GAIN ERROR vs SUPPLY VOLTAGE

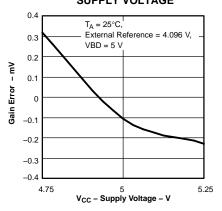


Figure 18.

## INTERNAL VOLTAGE REFERENCE vs FREE-AIR TEMPERATURE

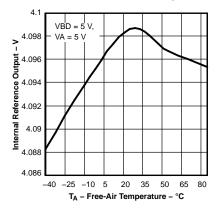


Figure 20.

#### SUPPLY CURRENT vs SAMPLE RATE

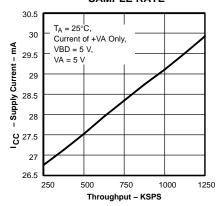


Figure 17.

#### OFFSET ERROR VS SUPPLY VOLTAGE

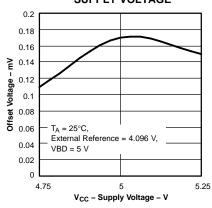


Figure 19.

#### GAIN ERROR vs FREE-AIR TEMPERATURE

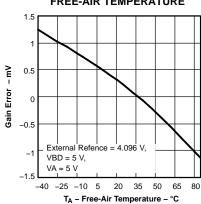


Figure 21.



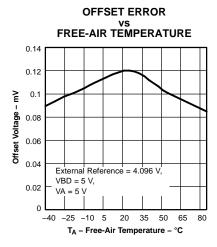


Figure 22.

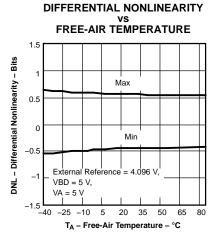


Figure 24.

DIFFERENTIAL NONLINEARITY

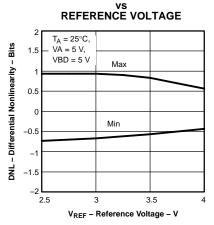


Figure 26.

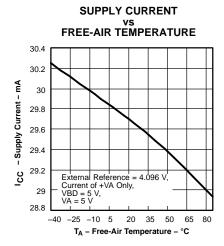


Figure 23.

# INTEGRAL NONLINEARITY vs FREE-AIR TEMPERATURE

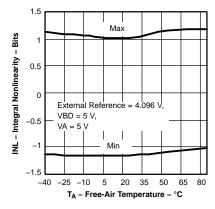


Figure 25.

# INTEGRAL NONLINEARITY VS REFERENCE VOLTAGE

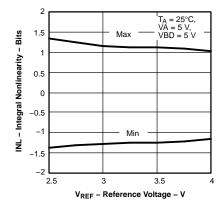
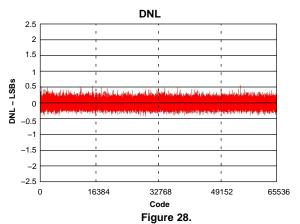
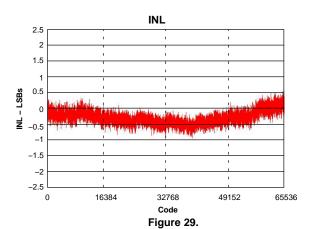
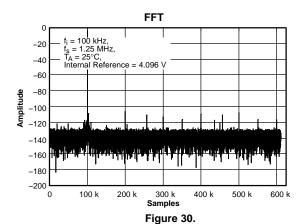


Figure 27.











### **APPLICATION INFORMATION**

#### MICROCONTROLLER INTERFACING

### ADS8406 to 8-Bit Microcontroller Interface

Figure 31 shows a parallel interface between the ADS8406 and a typical microcontroller using the 8-bit data bus. The BUSY signal is used as a falling-edge interrupt to the microcontroller.

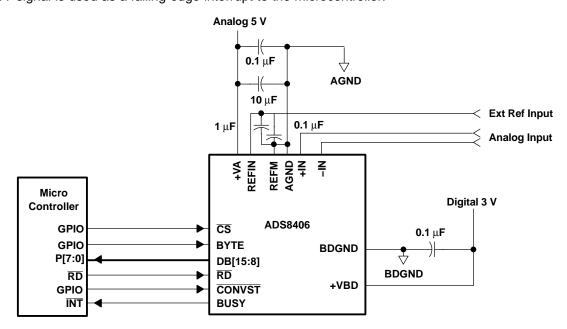


Figure 31. ADS8406 Application Circuitry (using external reference)

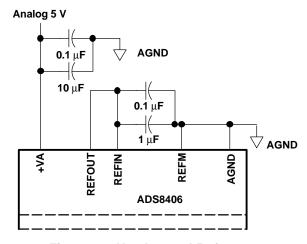


Figure 32. Use Internal Reference

## PRINCIPLES OF OPERATION

The ADS8406 is a high-speed successive approximation register (SAR) analog-to-digital converter (ADC). The architecture is based on charge redistribution, which inherently includes a sample/hold function. See Figure 31 for the application circuit for the ADS8406.

The conversion clock is generated internally. The conversion time of 650 ns is capable of sustaining a 1.25-MHz throughput.



## PRINCIPLES OF OPERATION (continued)

The analog input is provided to two input pins: +IN and -IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. While a conversion is in progress, both inputs are disconnected from any internal function.

### REFERENCE

The ADS8406 can operate with an external reference with a range from 2.5 V to 4.2 V. A 4.096-V internal reference is included. When internal reference is used, pin 2 (REFOUT) should be connected to pin 1 (REFIN) with a 0.1-µF decoupling capacitor and 1-µF storage capacitor between pin 2 (REFOUT) and pins 47 and 48 (REFM) (see Figure 33). The internal reference of the converter is double buffered. If an external reference is used, the second buffer provides isolation between the external reference and the CDAC. This buffer is also used to recharge all of the capacitors of the CDAC during conversion. Pin 2 (REFOUT) can be left unconnected (floating) if external reference is used.

### **ANALOG INPUT**

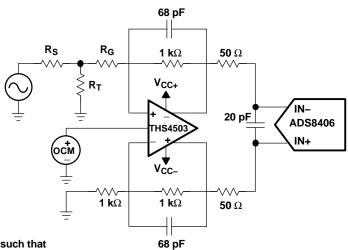
When the converter enters the hold mode, the voltage difference between the +IN and -IN inputs is captured on the internal capacitor array. Both +IN and -IN inputs have a range of -0.2 V to  $V_{ref}$  + 0.2 V. The input span (+IN - (-IN)) is limited to  $-V_{ref}$  to  $V_{ref}$ .

The input current on the analog inputs depends upon a number of factors: sample rate, input voltage, and source impedance. Essentially, the current into the ADS8406 charges the internal capacitor array during the sample period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (25 pF) to an 16-bit settling level within the acquisition time (150 ns) of the device. When the converter goes into the hold mode, the input impedance is greater than 1  $G\Omega$ .

Care must be taken regarding the absolute analog input voltage. To maintain the linearity of the converter, the +IN and -IN inputs and the span (+IN – (-IN)) should be within the limits specified. Outside of these ranges, the converter's linearity may not meet specifications. To minimize noise, low bandwidth input signals with low-pass filters should be used.

Care should be taken to ensure that the output impedance of the sources driving +IN and -IN inputs are matched. If this is not observed, the two inputs could have different setting time. This may result in offset error, gain error and linearity error which varies with temperature and input voltage.

A typical input circuit using TI's THS4503 is shown in Figure 33. Input from a single-ended source may be converted into a differential signal for the ADS8406 as shown in the figure. In case the source itself is differential, then the THS4503 may be used in differential input and differential output modes.



R<sub>G</sub>, R<sub>S</sub>, and R<sub>T</sub> should be chosen such that R<sub>G+</sub> R<sub>S</sub>  $\parallel$  R<sub>T</sub> = 1 k  $\Omega$  V<sub>OCM</sub> = 2 V, +V<sub>CC</sub> = 7 V, and -V<sub>CC</sub> = -7 V

Figure 33. Using the THS4503 With the ADS8406



# PRINCIPLES OF OPERATION (continued) DIGITAL INTERFACE

### **Timing And Control**

See the timing diagrams in the specifications section for detailed information on timing signals and their requirements.

The ADS8406 uses an internal oscillator generated clock which controls the conversion rate and in turn the throughput of the converter. No external clock input is required.

Conversions are initiated by bringing the  $\overline{\text{CONVST}}$  pin low for a minimum of 20 ns (after the 20 ns minimum requirement has been met, the  $\overline{\text{CONVST}}$  pin can be brought high), while  $\overline{\text{CS}}$  is low. The ADS8406 switches from the sample to the hold mode on the falling edge of the  $\overline{\text{CONVST}}$  command. A clean and low jitter falling edge of this signal is important to the performance of the converter. The BUSY output is brought high after  $\overline{\text{CONVST}}$  goes low. BUSY stays high throughout the conversion process and returns low when the conversion has ended.

Sampling starts as soon as the conversion is over when  $\overline{CS}$  is tied low or starts with the falling edge of  $\overline{CS}$  when BUSY is low.

Both  $\overline{RD}$  and  $\overline{CS}$  can be high during and before a conversion with one exception ( $\overline{CS}$  must be low when  $\overline{CONVST}$  goes low to initiate a conversion). Both the  $\overline{RD}$  and  $\overline{CS}$  pins are brought low in order to enable the parallel output bus with the conversion.

### **Reading Data**

The ADS8406 outputs full parallel data in two's complement format as shown in Table 1. The parallel output is active when  $\overline{CS}$  and  $\overline{RD}$  are both low. There is a minimal quiet zone requirement around the falling edge of  $\overline{CONVST}$ . This is 50 ns prior to the falling edge of  $\overline{CONVST}$  and 40 ns after the falling edge. No data read should be attempted within this zone. Any other combination of  $\overline{CS}$  and  $\overline{RD}$  sets the parallel output to 3-state. BYTE is used for multiword read operations. BYTE is used whenever lower bits of the converter result are output on the higher byte of the bus. Refer to Table 1 for ideal output codes.

**DESCRIPTION ANALOG VALUE DIGITAL OUTPUT** 2(+V<sub>ref</sub>) Full scale range 2'S COMPLEMENT Least significant bit (LSB) 2(+V<sub>ref</sub>)/65536 **BINARY CODE HEX CODE**  $(+V_{ref}) - 1 LSB$ +Full scale 0111 1111 1111 1111 7FFF 0 V 0000 0000 0000 0000 Midscale 0000 Midscale - 1 LSB 0 V- 1 LSB 1111 1111 1111 1111 **FFFF** - Full scale 1000 0000 0000 0000 8000  $(-V_{ref})$ 

Table 1. Ideal Input Voltages and Output Codes

The output data is a full 16-bit word (D15-D0) on DB15-DB0 pins (MSB-LSB) if BYTE is low.

The result may also be read on an 8-bit bus for convenience. This is done by using only pins DB15–DB8. In this case two reads are necessary: the first as before, leaving BYTE low and reading the 8 most significant bits on pins DB15–DB8, then bringing BYTE high. When BYTE is high, the low bits (D7–D0) appear on pins DB15–D8.

These multiword read operations can be done with multiple active  $\overline{RD}$  (toggling) or with  $\overline{RD}$  tied low for simplicity.

#### **Conversion Data Readout**

BYTE	DATA READ OUT					
BIIC	DB15-DB8 Pins	DB7-DB0 Pins				
High	D7-D0	All one's				
Low	D15-D8	D7-D0				



#### RESET

RESET is an asynchronous active low input signal (that works independently of  $\overline{CS}$ ). Minimum  $\overline{RESET}$  low time is 25 ns. Current conversion will be aborted no later than 50 ns after the converter is in the reset mode. In addition, all output latches are cleared (set to zero's) after  $\overline{RESET}$ . The converter goes back to normal operation mode no later than 20 ns after  $\overline{RESET}$  input is brought high.

The converter starts the first sampling period 20 ns after the rising edge of RESET. Any sampling period except for the one immediately after a RESET is started with the falling edge of the previous BUSY signal or the falling edge of CS, whichever is later.

Another way to reset the device is through the use of the combination of  $\overline{CS}$  and  $\overline{CONVST}$ . This is useful when the dedicated  $\overline{RESET}$  pin is tied to the system reset but there is a need to abort only the conversion in a specific converter. Since the BUSY signal is held high during the conversion, either one of these conditions triggers an internal self-clear reset to the converter just the same as a reset via the dedicated  $\overline{RESET}$  pin. The reset does not have to be cleared as for the dedicated  $\overline{RESET}$  pin. A reset can be started with either of the two following steps.

- Issue a CONVST when CS is low and a conversion is in progress. The falling edge of CONVST must satisfy
  the timing as specified by the timing parameter t<sub>su(AB)</sub> mentioned in the timing characteristics table to ensure
  a reset. The falling edge of CONVST starts a reset. Timing is the same as a reset using the dedicated
  RESET pin except the instance of the falling edge is replaced by the falling edge of CONVST.
- Issue a S while a conversion is in progress. The falling edge of S must satisfy the timing as specified by the timing parameter t<sub>su(AB)</sub> mentioned in the timing characteristics table to ensure a reset. The falling edge of S causes a reset. Timing is the same as a reset using the dedicated ESET pin except the instance of the falling edge is replaced by the falling edge of S.

### **POWER-ON INITIALIZATION**

RESET is not required after power on. An internal power-on-reset circuit generates the reset. To ensure that all of the registers are cleared, the three conversion cycles must be given to the converter after power on.

## **LAYOUT**

For optimum performance, care should be taken with the physical layout of the ADS8406 circuitry.

As the ADS8406 offers single-supply operation, it is often used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to achieve good performance from the converter.

The basic SAR architecture is sensitive to glitches or sudden changes on the power supply, reference, ground connections and digital inputs that occur just prior to latching the output of the analog comparator. Thus, driving any single conversion for an n-bit SAR converter, there are at least n *windows* in which large external transient voltages can affect the conversion result. Such glitches might originate from switching power supplies, nearby digital logic, or high power devices.

The degree of error in the digital output depends on the reference voltage, layout, and the exact timing of the external event.

On average, the ADS8406 draws very little current from an external reference, as the reference voltage is internally buffered. If the reference voltage is external and originates from an op amp, make sure that it can drive the bypass capacitor or capacitors without oscillation. A 0.1-µF bypass capacitor and a 1-µF storage capacitor are recommended from pin 1 (REFIN) directly to pin 48 (REFM). REFM and AGND should be shorted on the same ground plane under the device.

The AGND and BDGND pins should be connected to a clean ground point. In all cases, this should be the analog ground. Avoid connections which are close to the grounding point of a microcontroller or digital signal processor. If required, run a ground trace directly from the converter to the power supply entry point. The ideal layout consists of an analog ground plane dedicated to the converter and associated analog circuitry.



As with the AGND connections, +VA should be connected to a 5-V power supply plane or trace that is separate from the connection for digital logic until they are connected at the power entry point. Power to the ADS8406 should be clean and well bypassed. A 0.1-µF ceramic bypass capacitor should be placed as close to the device as possible. See Table 2 for the placement of the capacitor. In addition, a 1-µF to 10-µF capacitor is recommended. In some situations, additional bypassing may be required, such as a 100-µF electrolytic capacitor or even a Pi filter made up of inductors and capacitors—all designed to essentially low-pass filter the 5-V supply, removing the high frequency noise.

**Table 2. Power Supply Decoupling Capacitor Placement** 

POWER SUPPLY PLANE	CONVERTER ANALOG SIDE	CONVERTER DIGITAL SIDE
SUPPLY PINS	CONVERTER ANALOG SIDE	CONVERTER DIGITAL SIDE
Pin pairs that require shortest path to decoupling capacitors	(4,5), (8,9), (10,11), (13,15), (43,44), (45,46)	(24,25), (34, 35)
Pins that require no decoupling	12, 14	37

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### PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
ADS8406IBPFBR	Active	Production	TQFP (PFB)   48	2000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8406I B
ADS8406IBPFBR.B	Active	Production	TQFP (PFB)   48	2000   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	ADS8406I B
ADS8406IBPFBT	Active	Production	TQFP (PFB)   48	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8406I B
ADS8406IBPFBT.B	Active	Production	TQFP (PFB)   48	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	ADS8406I B

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

- (3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.
- (4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.
- (6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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# **PACKAGE OPTION ADDENDUM**

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PLASTIC QUAD FLATPACK



### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
   This drawing is subject to change without notice.
   Reference JEDEC registration MS-026.



PLASTIC QUAD FLATPACK



NOTES: (continued)

- 4. Publication IPC-7351 may have alternate designs.
- 5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PLASTIC QUAD FLATPACK



NOTES: (continued)



<sup>6.</sup> Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

<sup>7.</sup> Board assembly site may have different recommendations for stencil design.

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